

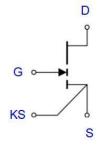
Description

SGN65N400DF is an enhancement mode GaN-on-silicon transistor. GaN is a wide band gap semiconductor with high power density. The gallium nitride transistor is characterized by no body diode, so the reverse recovery charge is zero.

Features

- 650 V enhancement mode power switch
- R_{DS(on)} =400mΩ
- I_{DS(max)} = 7.5A
- Easy gate drive requirements (0 V to 6 V)
- Very high switching frequency (> 10 MHz)
- Fast and controllable fall and rise times
- Zero reverse recovery loss

Device Information



Part Number	Marking Code	Package	Packing
SGN65N400DF	SGN65N400	DFN5×6	4000pcs/reel
•			р s

SGN65N400DF DFN5x6

SGN65N400DF Bottom View

G KS NC NC

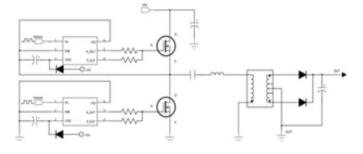


SGN65N400DF

E-mode GaN-on-Silicon FET

Applications

- Fast Battery Charging
- LED lighting drivers
- Power Factor Correction
- LLC Converters
- Wireless Power Transfer



Typical application circuit for LL

Absolute Maximum Ratings (Tc=25 ℃ unless otherwise specified)

Parameter	Symbol	Value	Unit	Condition
Drain-Source voltage	V _{DS}	650	V	
Gate-source voltage	V_{GS}	-7 to 6	V	
• · · · · · · · · · · ·	Ι _D	7.5	А	Tc=25℃
Continuous drain current*		5	А	Tc=100 ℃
Operation and storage	Tj	-55 to 150	°C	
temperature	Tstg	-55 to 150	°C	

* An Estimated Value



Thermal characteristics

Parameter	Symbol	Values	Unit	Note/Test Condition
Thermal resistance, junction-ambient	RthJA	37.1	°C/W	
Thermal resistance, junction-case	RthJC	1.9	°C/W	
Maximum reflow soldering temperature	Tsold	260	°C	MSL3

Electrical Characteristics (Tc=25 $^\circ C$ unless otherwise specified)

Typical Performance – Static

Demonster	Grande al	Values			11	T	
Parameter	Symbol	Min.	Туре.	Max.	Unit	Test condition	
Drain source breakdown voltage	BVDS	650	/	/	V	VGS=0V, ID=20μΑ	
Total drain	Inco	/	0.3	10	μA	VDS=650V, VGS=0V, Tj=25℃	
leakage current	IDSS	/	5	75	μΑ	VDS=650V, VGS=0V, Tj=150℃	
Gate-to-source current	IGSS	/	2	/	μΑ	VDS=0V, VGS=6V, Tj=25℃	
Static drain-source RDS(on-resistance	RDS(ON)	/	350	400	mΩ	VGS=6V, ID=3A, Tj=25℃	
		/	650	/	mΩ	VGS=6V, ID=3A, Tj=150℃	
Gate threshold voltage	VGS(th)	1.2	1.6	2.0	V	VDS=VGS, ID=3.5mA,	



E-mode GaN-on-Silicon FET

Typical Performance – Dynamic

_		Values			_	
Parameter	Symbol	Min	Туре	Max	Unit	Test condition
Input capacitance	C _{ISS}	/	32	/	pF	N 400V
Output capacitance	C _{oss}	/	9	/	pF	V _{DS} =400V, V _{GS} =0V,
Reverse transfer Capacitance	C _{RSS}	/	0.3	/	pF	f=1MHz
Output capacitance, energy Related	C _{OSS(er)}	/	15	/	рF	V _{DS} =0V to
Output capacitance time related	C _{OSS(tr)}	/	21	/	рF	400V,V _{GS} =0V
Total gate charge	Q _G	/	1.3	/	nC	
Gate-drain charge	Q_{GD}	/	0.33	/	nC	V _{DS} =400V, V _{GS} =0V to 6V
Gate-source charge	Q _{GS}	/	0.6	/	nC	
Gate Resistance	R _G	/	2.88	/	Ω	<i>f = f</i> res, Open drain



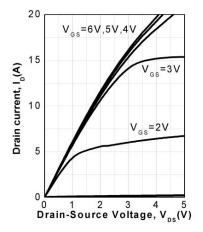


Fig.1 Typical output characteristics @ Tj=25 $^\circ\!\mathrm{C}$

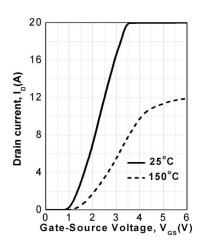


Fig.3 Typical transfer characteristics @ VDS=5V

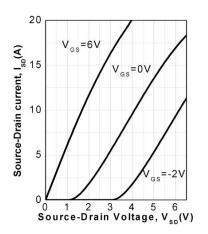


Fig.5 Typical reverse conduction characteristics

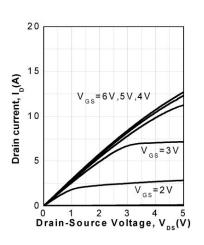


Fig.2 Typical output characteristics @ Tj=150 $^\circ C$

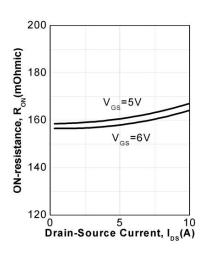


Fig.4 ON-resistance for various drain current @ 25 $^\circ\!\mathrm{C}$

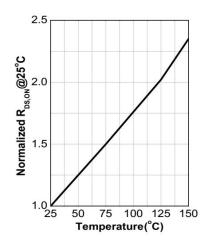


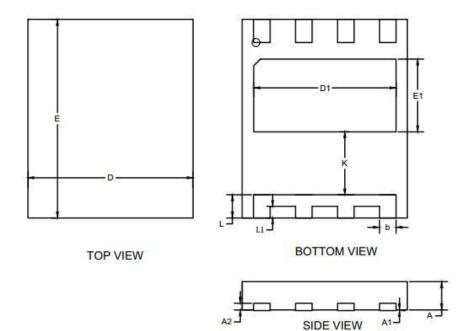
Fig.6 Normalized ON-resistance at various temperatures



E-mode GaN-on-Silicon FET

Package

Dimensions(mm)						
Symbol	Min.	Nom.	Max.			
А	0.8	0.85	0.9			
A1	-	0.02	0.05			
A2		0.2(REF)				
b	0.45	0.50	0.55			
D	4.90	5.00	5.10			
D1	4.20	4.30	4.40			
E	5.90	6.00	6.10			
E1	2.10	2.20	2.30			
е	1.27					
k	1.9	-	-			
L	0.65	0.7	0.75			





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